BUK7105-40ATE

N-channel TrenchPLUS standard level FET

Rev. 02 — 10 February 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. The devices include TrenchPLUS diodes for temperature sensing and ElectroStatic Discharge (ESD) protection. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

1.2 Features and benefits

- Allows responsive temperature monitoring due to integrated temperature sensor
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for standard level gate drive sources

1.3 Applications

Electrical Power Assisted Steering (EPAS)

Variable Valve Timing for engines

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 ^{\circ}C; T_j \le 175 ^{\circ}C$	-	-	40	V
Static cha	racteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A};$ $T_j = 25 \text{ C}; \text{ see } \frac{\text{Figure 7}}{\text{Figure 8}}; \text{ see}$	-	4.5	5	mΩ
S _{F(TSD)}	temperature sense diode temperature coefficient	$I_F = 250 \ \mu A; T_j \ge -55 \ ^{\circ}C;$ $T_j \le 175 \ ^{\circ}C$	-1.4	-1.54	-1.68	mV/K
V _{F(TSD)}	temperature sense diode forward voltage	$I_F = 250 \ \mu A; \ T_j = 25 \ ^{\circ}\!$	648	658	668	mV
V _{F(TSD)hys}	temperature sense diode forward voltage hysteresis	$I_F \le 250 \ \mu A; T_j = 25 \ ^{\circ}C;$ $I_F \ge 125 \ \mu A$	25	32	50	mV



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	Α	anode	mb	D A
3	D	drain		G A B A
4	K	cathode		(宏 平)
5	S	source	()()(3)()()	
mb	D	mounting base; connected to	1 2 4 5	s K
		drain	SOT426 (D2PAK)	mbl/317

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7105-40ATE	D2PAK	plastic single-ended surface-mounted package (D2PAK); 5 leads (one lead cropped)	SOT426

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Cumbal	Darameter	Conditions		Min	Max	I Imit
Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{°C}; T_j \le 175 \text{°C}$		-	40	V
V_{GS}	gate-source voltage			-20	20	V
I_D	drain current	$T_{mb} = 25 \text{C}; \text{ V}_{GS} = 10 \text{ V}; \text{ see } \underline{\text{Figure 2}}; \text{ see } \underline{\text{Figure 3}}$	[1]	-	155	Α
			[2]	-	75	Α
		$T_{mb} = 100 \text{C}$; $V_{GS} = 10 \text{V}$; see Figure 2	[2]	-	75	Α
I_{DM}	peak drain current	$T_{mb} = 25 \text{ C}$; $t_p \le 10 \mu\text{s}$; pulsed; see Figure 3		-	620	Α
P _{tot}	total power dissipation	$T_{mb} = 25 \text{°C}$; see Figure 1		-	272	W
I _{GS(CL)}	gate-source clamping	continuous		-	10	mA
	current	pulsed; $t_p = 5 \text{ ms}$; $\delta = 0.01$		-	50	mA
V _{isol(FET-TSD)}	FET to temperature sense diode isolation voltage			-100	100	V
T_{stg}	storage temperature			-55	175	$\mathcal C$
T _j	junction temperature			-55	175	$\mathcal C$
Source-drai	n diode					
I _S	source current	T _{mb} = 25 ℃	[1]	-	155	Α
			[2]	-	75	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s; \ pulsed; \ T_{mb} = 25 \ ^{\circ}\!$		-	620	Α
Avalanche r	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 75 A; V_{sup} ≤ 40 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	1.46	J
Electrostation	c discharge					
V _{esd}	electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	6	kV

^[1] Current is limited by power dissipation chip rating.

^[2] Continuous current is limited by package.

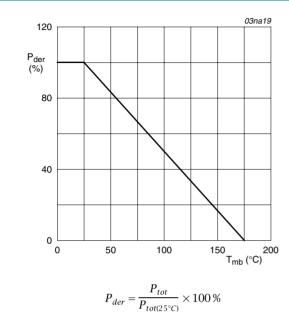


Fig 1. Normalized total power dissipation as a function of mounting base temperature

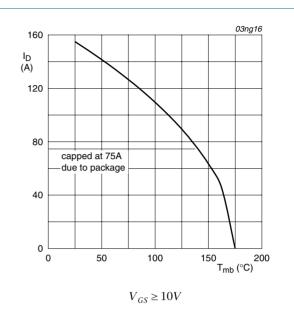
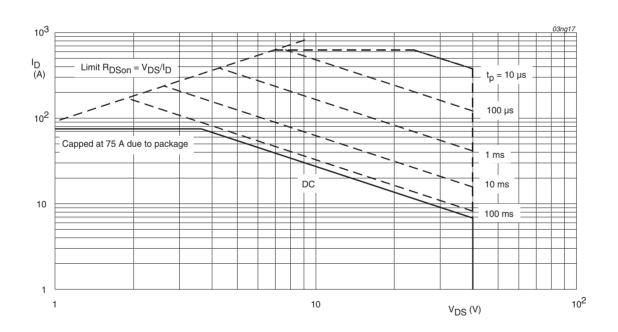


Fig 2. Continuous drain current as a function of mounting base temperature



 $T_{mb} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed-circuit board; minimum footprint	-	50	-	K/W
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	-	0.55	K/W

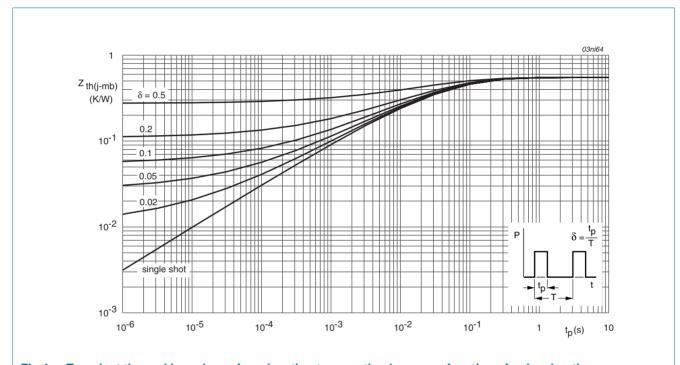


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	40	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 ^{\circ}\text{C}$	36	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see Figure 9	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 9	1	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ C}$; see Figure 9	-	-	4.4	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.1	10	μΑ
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 ^{\circ}\text{C}$	-	-	250	μΑ
V _{(BR)GSS} gate-source breakdown voltage	gate-source breakdown voltage	$I_G = 1 \text{ mA}$; $V_{DS} = 0 \text{ V}$; $T_j \le 175 \text{ C}$; $T_j \ge -55 \text{ C}$	20	22	-	V
		$I_G = -1 \text{ mA}; V_{DS} = 0 \text{ V}; T_j \le 175 \text{ C};$ $T_j \ge -55 \text{ C}$	20	22	-	V
I _{GSS}	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	22	1000	nA
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	22	1000	nA
		V _{DS} = 0 V; V _{GS} = 10 V; T _j = 175 °C	-	-	10	μΑ
		V _{DS} = 0 V; V _{GS} = -10 V; T _j = 175 °C	-	-	10	μΑ
R _{DSon} drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 25 \text{ C};$ see Figure 7; see Figure 8	-	4.5	5	mΩ	
		$V_{GS} = 10 \text{ V}; I_D = 50 \text{ A}; T_j = 175 ^{\circ}\text{C};$ see Figure 7; see Figure 8	-	-	9.5	mΩ
$V_{F(TSD)}$	temperature sense diode forward voltage	$I_F = 250 \ \mu A; \ T_j = 25 \ ^{\circ}C$	648	658	668	mV
S _{F(TSD)}	temperature sense diode temperature coefficient	$I_F = 250 \ \mu A; \ T_j \ge -55 \ ^{\circ}C; \ T_j \le 175 \ ^{\circ}C$	-1.4	-1.54	-1.68	mV/K
V _{F(TSD)hys}	temperature sense diode forward voltage hysteresis	$I_F \le 250 \ \mu A; \ I_F \ge 125 \ \mu A; \ T_j = 25 \ ^{\circ}C$	25	32	50	mV
Dynamic o	haracteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	118	-	nC
Q _{GS}	gate-source charge	$T_j = 25 \text{°C}$; see Figure 14	-	16	-	nC
Q_{GD}	gate-drain charge		-	57	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4500	-	pF
C _{oss}	output capacitance	$T_j = 25 \text{°C}$; see Figure 12	-	1500	-	pF
C _{rss}	reverse transfer capacitance		-	960	-	pF

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	35	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	115	-	ns
t _{d(off)}	turn-off delay time		-	155	-	ns
t _f	fall time		-	110	-	ns
L _D	internal drain inductance	from upper edge of mounting base to centre of die; $T_j = 25 ^{\circ}\text{C}$	-	2.5	-	nΗ
L _S	internal source inductance	from source lead to source bond pad; $T_j = 25 \ \mbox{$^{\circ}$}$	-	7.5	-	nΗ
Source-dr	ain diode					
V_{SD}	source-drain voltage	$I_S = 40 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 17</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = -10 \text{ V}$;	-	96	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	224	-	nC

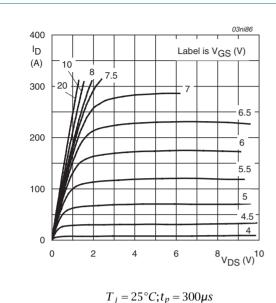


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

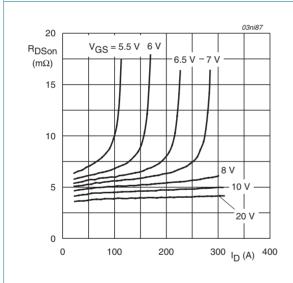
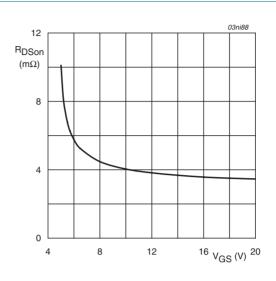


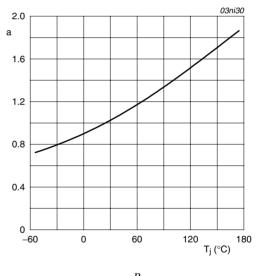
Fig 7. Drain-source on-state resistance as a function of drain current; typical values

 $T_i = 25^{\circ}C; t_p = 300 \mu s$



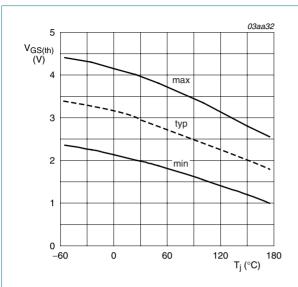
 $T_j = 25^{\circ}C; I_D = 50A$

Fig 6. Drain-source on-state resistance as a function of gate-source voltage; typical values



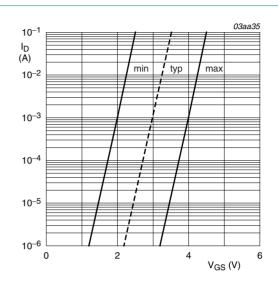
 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C}}$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



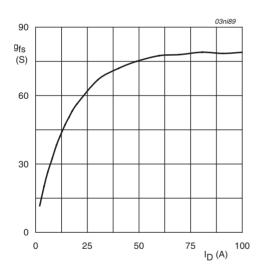
 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



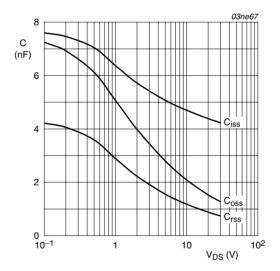
 $T_{j} = 25 \,^{\circ}C; V_{DS} = 5V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



 $T_i = 25^{\circ}C; V_{DS} = 25V$

Fig 11. Forward transconductance as a function of drain current; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

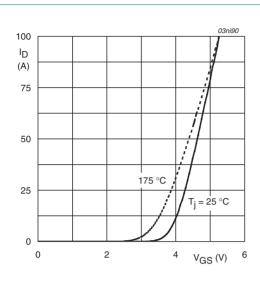


Fig 13. Transfer characteristics: drain current as a function of gate-source voltage; typical values

 $V_{DS} = 25V$

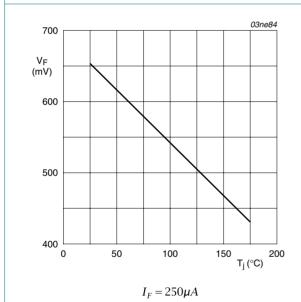
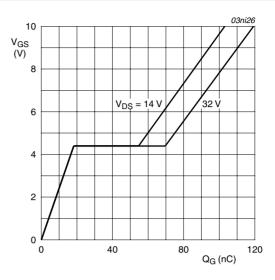
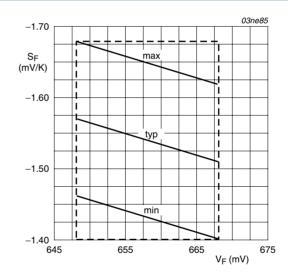


Fig 15. Forward voltage of temperature sense diode as a function of junction temperature; typical values



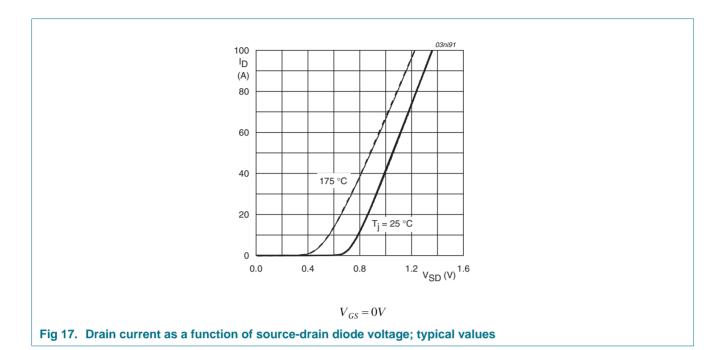
 $T_i = 25^{\circ}C; I_D = 25A$

Fig 14. Gate-source voltage as a function of turn-on gate charge; typical values



 V_F at $T_j = 25^{\circ}C$; $I_F = 250 \mu A$

Fig 16. Temperature coefficient of temperature sense diode as a function of forward voltage; typical values



Package outline

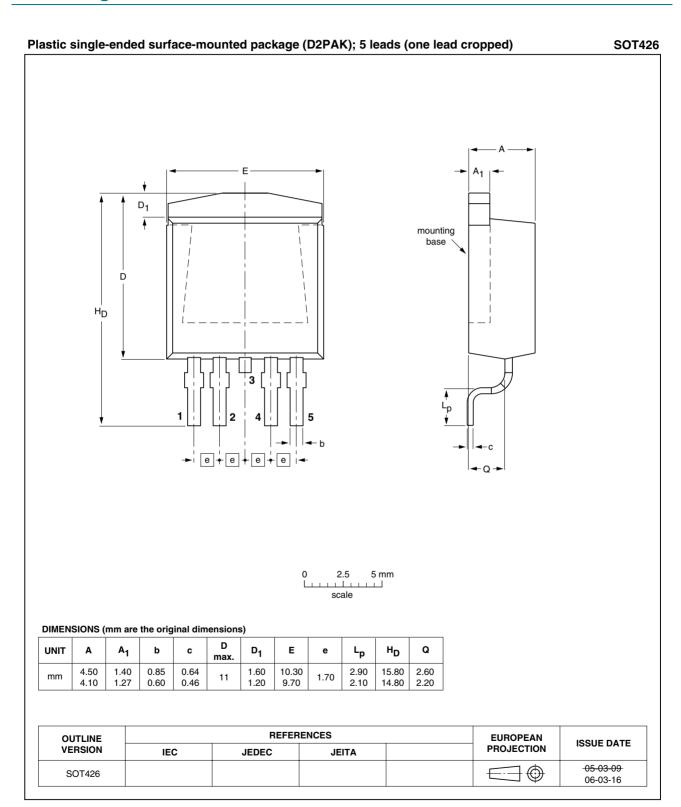


Fig 18. Package outline SOT426 (D2PAK)

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8. Revision history

Table 7. Revision history

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Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7105-40ATE_2	20090210	Product data sheet	-	BUK71_7905_40ATE-01
Modifications:	 The format of this data sheet has been redesigned to comply with the new identit guidelines of NXP Semiconductors. Legal texts have been adapted to the new company name where appropriate. 			
	 Type numb 	er BUK7105-40ATE sepa	rated from data sheet B	JK71_7905_40ATE-01.
BUK71_7905_40ATE-01 (9397 750 11694)	20030820	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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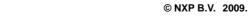
BUK7105-40ATE

N-channel TrenchPLUS standard level FET

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